Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/712,364	KOBAYASHI, KAZUO
Examiner	Art Unit
W. David Coleman	2823

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST 2.0.1 Text search only, Applicants dice a wafer with a saw and laser wherein the wafer has an adhesive backing.	3/14/2005	WDC		
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